# **BUK9226-75A**



# N-channel TrenchMOS logic level FET Rev. 02 — 27 January 2011

**Product data sheet** 

#### **Product profile** 1.

## 1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

## 1.2 Features and benefits

- AEC Q101 compliant
- Low conduction losses due to low on-state resistance
- Suitable for logic level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

## 1.3 Applications

- 12 V, 24 V and 42 V loads
- Automotive and general purpose power switching

Motors, lamps and solenoids

#### 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C	-	-	75	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 5 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	45	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	-	114	W
Static ch	aracteristics					
R <sub>DSon</sub>	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C}$	-	-	29	mΩ
	resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C}$	-	20.9	24.6	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 13</u> ; see <u>Figure 12</u>	-	22.1	26	mΩ
Avalanch	ne ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 49 A; $V_{sup} \le 75$ V; $R_{GS}$ = 50 $\Omega$ ; $V_{GS}$ = 5 V; $T_{j(init)}$ = 25 °C; unclamped	-	-	120	mJ



# 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol		
1	G	gate		-		
2	D	drain	mb	D		
3	S	source				
mb	D	mounting base; connected to drain	1 3	mbb076 S		
			SOT428 (DPAK)			

# 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK9226-75A	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428

## 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

$\begin{array}{c} V_{DS} & drain\text{-source voltage} & T_j \geq 25~^\circ\text{C}; \ T_j \leq 175~^\circ\text{C} & - & 75 \\ V_{DGR} & drain\text{-gate voltage} & R_{GS} = 20~\text{k}\Omega & - & 75 \\ V_{GS} & gate\text{-source voltage} & -10 & 10 \\ I_D & drain current & T_{mb} = 25~^\circ\text{C}; \ V_{GS} = 5~\text{V}; \ \text{see Figure 1}; \\ see \ \overline{\text{Figure 3}} & - & 32 \\ I_{DM} & \text{peak drain current} & T_{mb} = 25~^\circ\text{C}; \ \text{pulsed}; \ t_p \leq 10~\text{µs}; & 11 \\ P_{tot} & \text{total power dissipation} & T_{mb} = 25~^\circ\text{C}; \ \text{see Figure 2} & - & 114 \\ T_{stg} & \text{storage temperature} & -55 & 175 \\ T_j & \text{junction temperature} & -55 & 175 \\ V_{GSM} & \text{peak gate-source voltage} & \text{pulsed}; \ t_p \leq 50~\text{µs} & -15 & 15 \\ \hline \textbf{Source-drain diode} & & & & & & & & & & \\ I_{SM} & \text{peak source current} & T_{mb} = 25~^\circ\text{C} & - & 45 \\ \hline \textbf{Avalanche ruggedness} & & & & & & & & & & & \\ \hline \end{array}$		<del></del>			
$\begin{array}{c} V_{DGR} & \text{drain-gate voltage} & R_{GS} = 20 \text{ k}\Omega & - & 75 \\ V_{GS} & \text{gate-source voltage} & -10 & 10 \\ I_{D} & \text{drain current} & T_{mb} = 25  ^{\circ}\text{C};  V_{GS} = 5  \text{V};  \text{see Figure 1}; \\ \text{see Figure 3} & - & 32 \\ I_{DM} & \text{peak drain current} & T_{mb} = 25  ^{\circ}\text{C};  \text{pulsed};  t_{p} \leq 10  \mu\text{s}; & 11 \\ \text{T}_{stg} & \text{storage temperature} & -55 & 175 \\ T_{j} & \text{junction temperature} & -55 & 175 \\ V_{GSM} & \text{peak gate-source voltage} & \text{pulsed};  t_{p} \leq 50  \mu\text{s} & -15 & 15 \\ \hline \textbf{Source-drain diode} & & & & & & & & & \\ I_{SM} & \text{peak source current} & T_{mb} = 25  ^{\circ}\text{C} & - & 45 \\ I_{SM} & \text{peak source current} & \text{pulsed};  t_{p} \leq 10  \mu\text{s};  T_{mb} = 25  ^{\circ}\text{C} & - & 182 \\ \hline \textbf{Avalanche ruggedness} & & & & & & & & & \\ \hline \end{array}$	Parameter	Conditions	Min	Max	Unit
$\begin{array}{c} V_{GS} & \text{gate-source voltage} \\ I_D \\ I$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C	-	75	V
$I_{D} \  \   \frac{T_{mb} = 25  ^{\circ}\text{C};  V_{GS} = 5  V;  \text{see Figure 1};  \text{see Figure 1};  \text{see Figure 3}}{T_{mb} = 100  ^{\circ}\text{C};  V_{GS} = 5  V;  \text{see Figure 1}}  -  32}$ $I_{DM} \  \   \text{peak drain current} \  \   \frac{T_{mb} = 25  ^{\circ}\text{C};  \text{pulsed};  t_p \leq 10  \mu\text{s}; }{\text{see Figure 3}}  -  182}$ $P_{tot} \  \   \text{total power dissipation} \  \   T_{mb} = 25  ^{\circ}\text{C};  \text{see Figure 2}  -  114}$ $T_{stg} \  \   \text{storage temperature}  -  -55  175$ $T_{j} \  \   \text{junction temperature}  -  -55  175}$ $V_{GSM} \  \   \text{peak gate-source voltage}  \text{pulsed};  t_p \leq 50  \mu\text{s}  -15  15}$ $Source-drain  diode$ $I_{S} \  \   \text{source current}  T_{mb} = 25  ^{\circ}\text{C}  -  45$ $I_{SM} \  \   \text{peak source current}  \text{pulsed};  t_p \leq 10  \mu\text{s};  T_{mb} = 25  ^{\circ}\text{C}  -  182}$ $Avalanche  ruggedness$	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	75	V
	gate-source voltage		-10	10	V
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	drain current		-	45	Α
$see \   \frac{ \   Figure \ 3 \ }{ \   See \   Figure \ 3 \ } $ $P_{tot} \qquad total \ power \ dissipation \qquad T_{mb} = 25 \ ^{\circ}C; \ see \   \frac{Figure \ 2 \ }{ \   } - 114 \ $ $T_{stg} \qquad storage \ temperature \qquad -55 \qquad 175 \ $ $T_{j} \qquad junction \ temperature \qquad -55 \qquad 175 \ $ $V_{GSM} \qquad peak \ gate-source \ voltage \qquad pulsed; \ t_{p} \le 50 \ \mu s \qquad -15 \qquad 15 \ $ $Source-drain \ diode \qquad \qquad -15 \qquad 15 \ $ $Source-drain \ diode \qquad \qquad -15 \qquad 15 \ $ $Source \ current \qquad T_{mb} = 25 \ ^{\circ}C \qquad - 45 \ $ $I_{SM} \qquad peak \ source \ current \qquad pulsed; \ t_{p} \le 10 \ \mu s; \ T_{mb} = 25 \ ^{\circ}C \qquad - 182 \ $ $Avalanche \ ruggedness \qquad - 182 \ $		$T_{mb}$ = 100 °C; $V_{GS}$ = 5 V; see <u>Figure 1</u>	-	32	Α
$T_{stg}$ storage temperature -55 175 $T_j$ junction temperature -55 175 $V_{GSM}$ peak gate-source voltage pulsed; $t_p ≤ 50 \ \mu s$ -15 15 $Source-drain \ diode$ $T_{mb} = 25 \ ^{\circ}C$ - 45 $I_{SM}$ peak source current pulsed; $t_p ≤ 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$ - 182 $Avalanche \ ruggedness$	peak drain current	11 7 P 1 7	<u>11</u> -	182	Α
$T_j$ junction temperature -55 175 $V_{GSM}$ peak gate-source voltage pulsed; $t_p ≤ 50 \ \mu s$ -15 15 $\frac{1}{5}$ Source-drain diode $T_{mb} = 25 \ ^{\circ}C$ - 45 $T_{mb} = 25 \ ^{\circ}C$ - 182 Avalanche ruggedness	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	114	W
$V_{GSM}$ peak gate-source voltage pulsed; $t_p \le 50~\mu s$ -15 15 Source-drain diode $I_S$ source current $T_{mb} = 25~^{\circ}C$ - 45 $I_{SM}$ peak source current pulsed; $t_p \le 10~\mu s$ ; $T_{mb} = 25~^{\circ}C$ - 182 Avalanche ruggedness	storage temperature		-55	175	°C
Source-drain diode $I_S \qquad \text{source current} \qquad T_{mb} = 25  ^{\circ}\text{C} \qquad - \qquad 45$ $I_{SM} \qquad \text{peak source current} \qquad \text{pulsed; } t_p \leq 10   \mu\text{s; } T_{mb} = 25  ^{\circ}\text{C} \qquad - \qquad 182$ Avalanche ruggedness	junction temperature		-55	175	°C
$I_{S}$ source current $I_{mb} = 25  ^{\circ}\text{C}$ - 45 $I_{SM}$ peak source current pulsed; $I_{p} \le 10  \mu \text{s}$ ; $I_{mb} = 25  ^{\circ}\text{C}$ - 182 Avalanche ruggedness	peak gate-source voltage	pulsed; t <sub>p</sub> ≤ 50 μs	-15	15	V
$I_{SM}$ peak source current pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$ - 182 <b>Avalanche ruggedness</b>	diode				
Avalanche ruggedness	source current	T <sub>mb</sub> = 25 °C	-	45	Α
	peak source current	pulsed; $t_p \le 10 \mu s$ ; $T_{mb} = 25  ^{\circ}C$	-	182	Α
	ıggedness				
$ \begin{array}{ll} {\sf E}_{\sf DS(AL)S} & {\sf non\text{-repetitive drain-source}} & {\sf I}_{\sf D} = 49 \; {\sf A;  V}_{\sf sup} \leq 75 \; {\sf V;  R}_{\sf GS} = 50 \; \Omega; \\ & {\sf avalanche  energy} & {\sf V}_{\sf GS} = 5 \; {\sf V;  T}_{\sf j(init)} = 25 \; {\sf ^{\circ}C;  unclamped} \end{array} $	non-repetitive drain-source avalanche energy	$I_D$ = 49 A; $V_{sup}$ ≤ 75 V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 5 V; $T_{j(init)}$ = 25 °C; unclamped	-	120	mJ
DS(AL)S		drain-source voltage drain-gate voltage gate-source voltage drain current  peak drain current  total power dissipation storage temperature junction temperature peak gate-source voltage  diode source current peak source current ggedness non-repetitive drain-source	drain-source voltage $T_j \ge 25  ^{\circ}\text{C};  T_j \le 175  ^{\circ}\text{C}$ drain-gate voltage $R_{GS} = 20  \text{k}\Omega$ gate-source voltage $R_{GS} = 20  \text{k}\Omega$ $T_{mb} = 25  ^{\circ}\text{C};  V_{GS} = 5  \text{V};  \text{see}  \frac{\text{Figure 1}}{1};  \text{see}  \frac{\text{Figure 3}}{1}$ $T_{mb} = 100  ^{\circ}\text{C};  V_{GS} = 5  \text{V};  \text{see}  \frac{\text{Figure 1}}{1};  \text{see}  \frac{\text{Figure 3}}{1}$ peak drain current $T_{mb} = 25  ^{\circ}\text{C};  \text{pulsed};  t_p \le 10  \mu\text{s};  \text{see}  \frac{\text{Figure 2}}{1}$ total power dissipation $T_{mb} = 25  ^{\circ}\text{C};  \text{see}  \frac{\text{Figure 2}}{1}$ storage temperature junction temperature peak gate-source voltage pulsed; $t_p \le 50  \mu\text{s}$ $\frac{\text{diode}}{1}$ source current $T_{mb} = 25  ^{\circ}\text{C}$ peak source current $T_{mb} = 25  ^{\circ}\text{C}$ pulsed; $t_p \le 10  \mu\text{s};  T_{mb} = 25  ^{\circ}\text{C}$ $\frac{\text{ggedness}}{1}$ non-repetitive drain-source $I_D = 49  \text{A};  V_{sup} \le 75  \text{V};  R_{GS} = 50  \Omega;$	$ \begin{array}{llllllllllllllllllllllllllllllllllll$	drain-source voltage $T_j \ge 25  ^{\circ}\text{C};  T_j \le 175  ^{\circ}\text{C}$ - 75 drain-gate voltage $R_{GS} = 20  \text{k}\Omega$ - 75 gate-source voltage -10 10 drain current $T_{mb} = 25  ^{\circ}\text{C};  V_{GS} = 5  \text{V};  \text{see Figure 1};  \text{see Figure 3}$ $T_{mb} = 100  ^{\circ}\text{C};  V_{GS} = 5  \text{V};  \text{see Figure 1}$ - 32 peak drain current $T_{mb} = 25  ^{\circ}\text{C};  \text{pulsed};  t_p \le 10  \mu \text{s};  \text{II}$ - 182 see Figure 3 total power dissipation $T_{mb} = 25  ^{\circ}\text{C};  \text{see Figure 2}$ - 114 storage temperature -55 175 junction temperature -55 175 peak gate-source voltage pulsed; $t_p \le 50  \mu \text{s}$ -15 15 diode source current $T_{mb} = 25  ^{\circ}\text{C};  \text{puse 3};  T_{mb} = 25  ^{\circ}\text{C};  \text{see Figure 2}$ - 45 peak source current $T_{mb} = 25  ^{\circ}\text{C}$ - 45 peak source current $T_{mb} = 25  ^{\circ}\text{C}$ - 182 tiggedness non-repetitive drain-source $I_D = 49  \text{A};  V_{sup} \le 75  \text{V};  R_{GS} = 50  \Omega;$ - 120

[1] Peak drain current is limited by chip, not package.

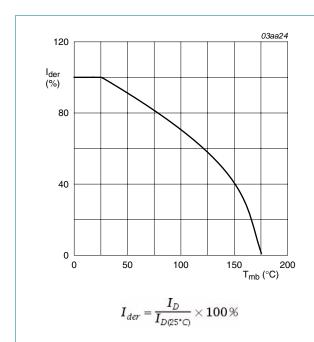


Fig 1. Normalized continuous drain current as a function of mounting base temperature

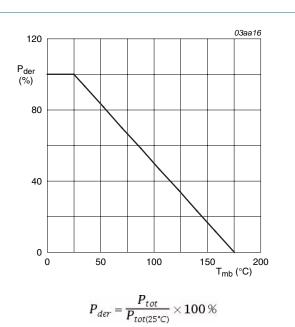
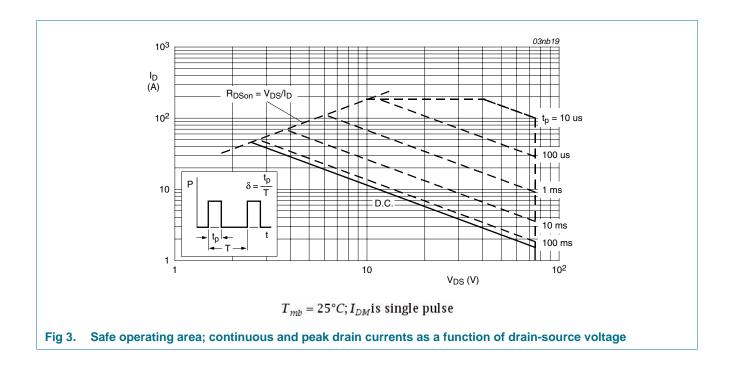


Fig 2. Normalized total power dissipation as a function of mounting base temperature



## 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{\text{th(j-mb)}}$	thermal resistance from junction to mounting base	see Figure 4	-	-	1.3	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	minimum footprint ; FR4 board	-	71.4	-	K/W

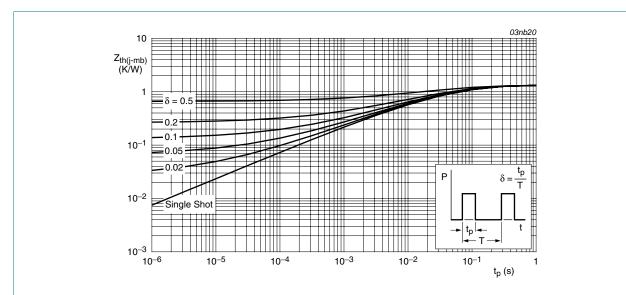


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

## 6. Characteristics

Table 6. Characteristics

		0 1141		_		
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
	racteristics					
$V_{(BR)DSS}$	drain-source breakdown	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	75	-	-	V
	voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	70	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	$I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = 175 \text{ °C}$ ; see Figure 11	0.5	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 25$ °C; see Figure 11	1	1.5	2	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = -55$ °C; see Figure 11	-	-	2.3	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	10	μΑ
		$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
I <sub>GSS</sub>	gate leakage current	V <sub>GS</sub> = 10 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	2	100	nA
		$V_{GS} = -10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 175 ^{\circ}\text{C};$ see <u>Figure 12</u> ; see <u>Figure 13</u>	-	-	54.6	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C}$	-	-	29	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C}$	-	20.9	24.6	$m\Omega$
		$V_{GS} = 5 \text{ V}$ ; $I_D = 25 \text{ A}$ ; $T_j = 25 \text{ °C}$ ; see Figure 13; see Figure 12	-	22.1	26	mΩ
Dynamic	characteristics					
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	2340	3120	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 14</u>	-	319	383	pF
C <sub>rss</sub>	reverse transfer capacitance		-	215	295	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 5 \text{ V};$	-	24	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \Omega; T_j = 25 ^{\circ}C$	-	141	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	142	-	ns
t <sub>f</sub>	fall time		-	108	-	ns
L <sub>D</sub>	internal drain inductance	measured from drain lead from package to centre of die ; $T_j = 25$ °C	-	2.5	-	nΗ
L <sub>S</sub>	internal source inductance	measured from source lead from package to source bond pad ; $T_j = 25  ^{\circ}\text{C}$	-	7.5	-	nΗ
Source-di	rain diode					
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 15</u>	-	0.85	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = 100 \text{ A/}\mu\text{s};$ $V_{GS} = -10 \text{ V}; V_{DS} = 30 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	49	-	ns
Q <sub>r</sub>	recovered charge	$I_S = 20 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = -10 \text{ V}$ ; $V_{DS} = 30 \text{ V}$ ; $T_i = 25 \text{ °C}$	-	115	-	nC

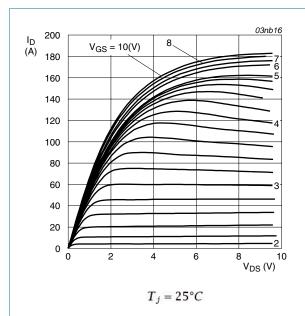


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

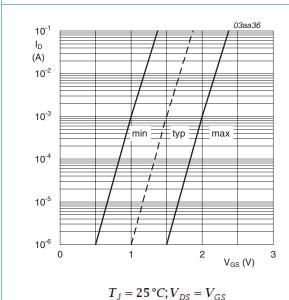
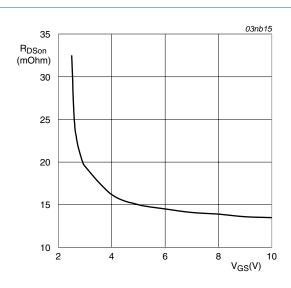
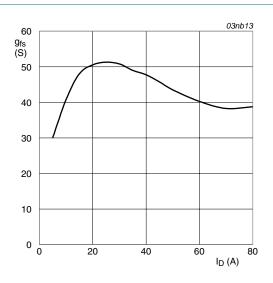


Fig 7. Sub-threshold drain current as a function of gate-source voltage



 $T_j = 25^{\circ}C; I_D = 25A$ 

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values



 $T_j = 25^{\circ}C; V_{DS} = 25V$ 

Fig 8. Forward transconductance as a function of drain current; typical values

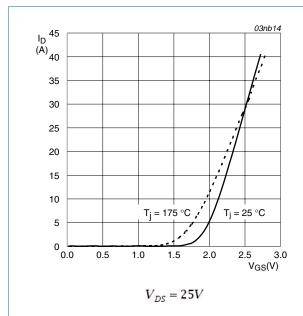


Fig 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values

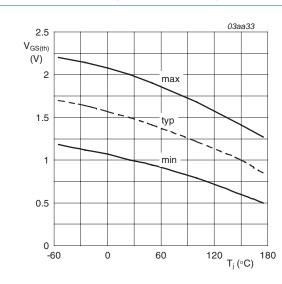
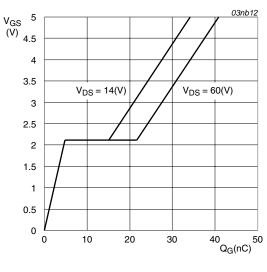


Fig 11. Gate-source threshold voltage as a function of junction temperature

 $I_D = 1mA; V_{DS} = V_{GS}$ 



 $T_j = 25^{\circ}C; I_D = 25A$ 

Fig 10. Gate-source voltage as a function of turn-on gate charge; typical values

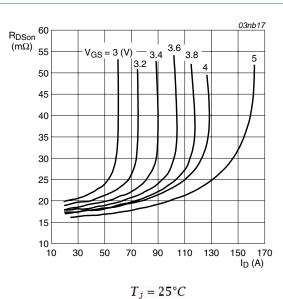


Fig 12. Drain-source on-state resistance as a function of drain current; typical values

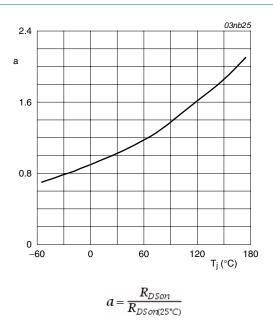


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

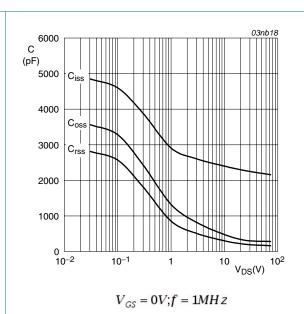


Fig 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical

values

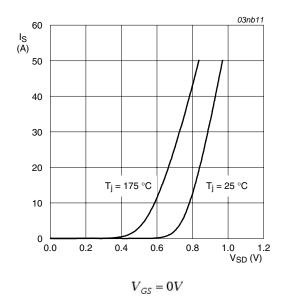


Fig 15. Reverse diode current as a function of reverse diode voltage; typical values

## 7. Package outline

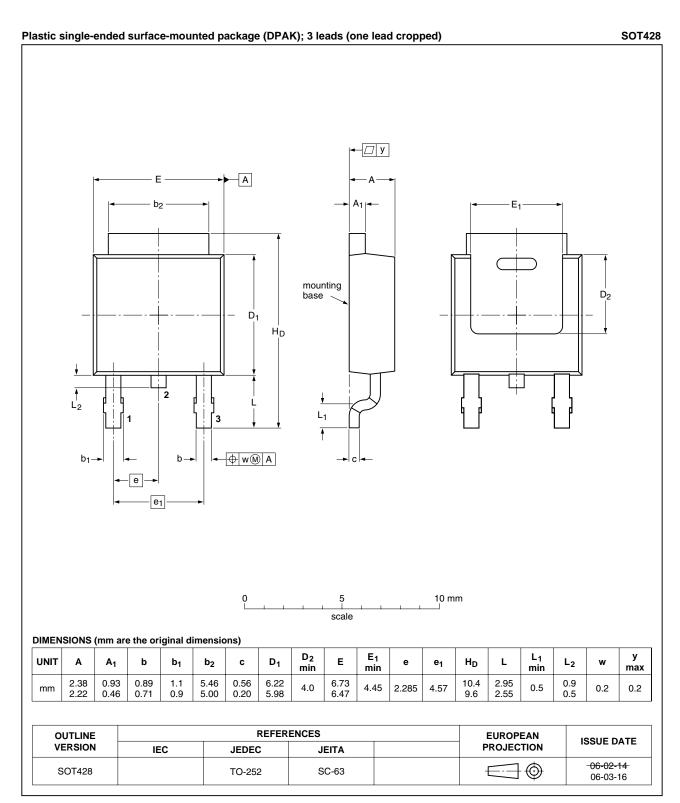


Fig 16. Package outline SOT428 (DPAK)



## 8. Revision history

### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes		
BUK9226-75A v.2	20110127	Product data sheet	-	BUK9226_75A v.1		
Modifications:	<ul> <li>The format of this data sheet has been redesigned to comply with the new identity guideli of NXP Semiconductors.</li> </ul>					
<ul> <li>Legal texts have been adapted to the new company name where appropriate.</li> </ul>						
BUK9226_75A v.1	20001010	Product specification	-	-		

## 9. Legal information

#### 9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <a href="http://www.nxp.com">http://www.nxp.com</a>.

#### 9.2 Definitions

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## N-channel TrenchMOS logic level FET

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